TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC4015BP,TC4015BF,TC4015BFN

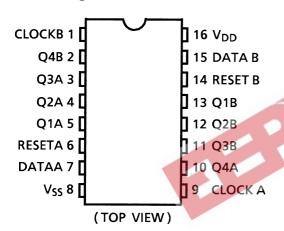
TC4015B Dual 4-Stage Static Shift Register (with serial input/parallel output)

TC4015B contains two circuits of 4 stage shift registers and the independent output is drived from each stage. As all the D type flip-flops of every stage have common RESET input, asynchronous clear operation can be achieved by an external signal at arbitrary timing. The flip-flop of each stage is triggered by rising edge of CLOCK input.

RESET input of "H" level resets the contents of all the stages to "L" regardless of CLOCK and DATA inputs and all of data outputs Q1 through Q4 become "L".

This can be used for converting serial data to palallel one and for ring counters of any numbering systems.

### **Pin Assignment**



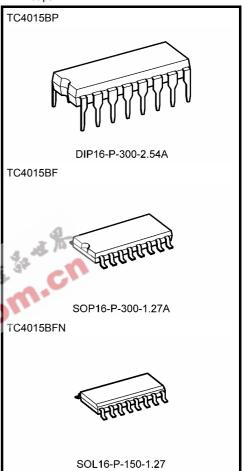
#### **Truth Table**

	Outputs							
CLOCK∆	DATA	RESET	Q1	Q2	Q3	Q4		
	L L		L	Q1	Q2	Q3		
	Н	L	H Q1		Q2	Q3		
$\neg$	*	L	No Change					
*	* * H		L	L	L	L		

Δ: Level change

\*: Don't care

Note: xxxFN (JEDEC SOP) is not available in Japan.

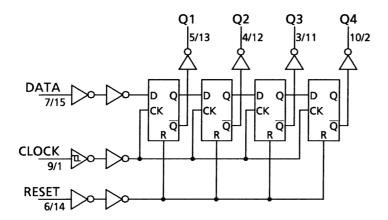


Weight

DIP16-P-300-2.54A : 1.00 g (typ.) SOP16-P-300-1.27A : 0.18 g (typ.) SOL16-P-150-1.27 : 0.13 g (typ.)

### **Logic Diagram**

#### 1/2 TC4015B



## **Absolute Maximum Ratings (Note)**

Characteristics	Symbol	Rating	Unit
DC supply voltage	$V_{DD}$	V <sub>SS</sub> – 0.5~V <sub>SS</sub> + 20	V
Input voltage	V <sub>IN</sub>	V <sub>SS</sub> – 0.5~V <sub>DD</sub> + 0.5	V
Output voltage	V <sub>OUT</sub>	V <sub>SS</sub> - 0.5~V <sub>DD</sub> + 0.5	V
DC input current	I <sub>IN</sub>	±10	mA
Power dissipation	PD	300 (DIP)/180 (SOIC)	mW
Operating temperature range	T <sub>opr</sub>	-40~85	ç
Storage temperature range	T <sub>stg</sub>	−65~1 <b>50</b>	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## Operating Ranges (V<sub>SS</sub> = 0 V) (Note)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
DC supply voltage	$V_{DD}$	_	3	_	18	V
Input voltage	V <sub>IN</sub>		0	_	$V_{DD}$	V

2

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either  $V_{DD}$  or  $V_{SS}$ .



## Static Electrical Characteristics ( $V_{SS} = 0 V$ )

		Sym-	Test Condition		-40°C		25°C			85°C		
Charac	teristics	bol		V <sub>DD</sub> (V)	Min	Max	Min	Тур.	Max	Min	Max	Unit
High-level output voltage			I <sub>OUT</sub>   < 1 μA  V <sub>IN</sub> = V <sub>SS</sub> , V <sub>DD</sub>	5	4.95	_	4.95	5.00	_	4.95	_	
		V <sub>OH</sub>		10	9.95	_	9.95	10.00	_	9.95	_	V
			VIN - VSS, VDD	15	14.95	_	14.95	15.00	_	14.95	_	
			I <sub>OUT</sub>   < 1 μA	5	_	0.05	_	0.00	0.05	_	0.05	
Low-level voltage	output	V <sub>OL</sub>	$V_{IN} = V_{SS}, V_{DD}$	10	_	0.05	_	0.00	0.05	_	0.05	V
			VIIV - VSS, VDD	15	_	0.05	_	0.00	0.05	_	0.05	
			V <sub>OH</sub> = 4.6 V	5	-0.61	_	-0.51	-1.0	_	-0.42	_	
			V <sub>OH</sub> = 2.5 V	5	-2.50	_	-2.10	-4.0	_	-1.70	_	mA
Output hig	gh current	IOH	V <sub>OH</sub> = 9.5 V	10	-1.50	_	-1.30	-2.2	_	-1.10	_	
			V <sub>OH</sub> = 13.5 V	15	-4.00	_	-3.40	-9.0	_	-2.80	_	
			$V_{IN} = V_{SS}, V_{DD}$									
		l <sub>OL</sub>	V <sub>OL</sub> = 0.4 V	5	0.61	_	0.51	1.2	_	0.42	_	mA
Output lov	v current		V <sub>OL</sub> = 0.5 V	10	1.50	_	1.30	3.2	_	1.10	_	
Output 10V	Vourient		V <sub>OL</sub> = 1.5 V	15	4.00	_	3.40	12.0	_	2.80	_	
			$V_{IN} = V_{SS}, V_{DD}$					4				
		V <sub>IH</sub>	V <sub>OUT</sub> = 0.5 V, 4.5 V	5	3.5	_	3.5	2.75	_	3.5	_	V
Input high	voltage		V <sub>OUT</sub> = 1.0 V, 9.0 V	10	7.0	-0.	7.0	5.50	<b>U</b>	7.0	_	
input nign	voltage		V <sub>OUT</sub> = 1.5 V, 13.5 V	15	11.0	% Z	11.0	8.25	_	11.0	_	v
			$ I_{OUT}  < 1 \mu A$			30	0,,					
			V <sub>OUT</sub> = 0.5 V, 4.5 V	5	<b>\</b> _\	1.5	_	2.25	1.5	_	1.5	
Input low y	Input low voltage		V <sub>OUT</sub> = 1.0 V, 9.0 V	10		3.0	_	4.50	3.0	_	3.0	V
input low voitage		V <sub>IL</sub>	$V_{OUT} = 1.5 \text{ V}, 13.5 \text{ V}$	15	_	4.0	_	6.75	4.0	_	4.0	
			I <sub>OUT</sub>   < 1 μA									
Input	"H" level	lін	V <sub>IH</sub> = 18 V	18		0.1	_	$10^{-5}$	0.1	_	1.0	μΑ
current	"L" level	I <sub>Ι</sub> L	$V_{IL} = 0 V$	18	_	-0.1	_	$-10^{-5}$	-0.1	_	-1.0	μΛ
	Quiescent supply current		V <sub>IN</sub> = V <sub>SS</sub> , V <sub>DD</sub> (Note)	5	_	5	_	0.005	5	_	150	
Quiescent current				10	_	10	_	0.010	10	_	300	μА
			(140(e)	15	_	20	_	0.015	20	—	600	

3

Note: All valid input combinations.



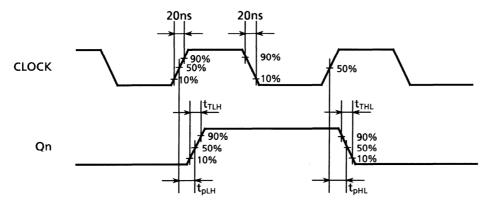
## Dynamic Electrical Characteristics (Ta = 25°C, $V_{SS}$ = 0 V, $C_L$ = 50 pF)

Characteristics	Symbol	Test Condition	Min	Typ. Max		Unit	
Characteristics	Symbol		V <sub>DD</sub> (V)	IVIIII	Тур.	IVIAX	Offic
Output transition time			5	_	70	200	
	t <sub>TLH</sub>	_	10	_	35	100	ns
(low to high)			15	_	30	80	
Output transition time			5	_	70	200	
(high to low)	t <sub>THL</sub>	_	10	_	35	100	ns
(High to low)			15	_	30	80	
Propagation delay time	<b>+</b>		5	_	130	320	
(CLOCK-Q)	t <sub>pLH</sub>	_	10	_	60	160	ns
(CLOCK-Q)	t <sub>pHL</sub>		15	_	50	120	
Propagation delay time			5	_	90	400	
(RESET-Q)	t <sub>pHL</sub>	_	10	_	45	200	ns
(NEOLT-Q)			15	_	40	160	
	f <sub>CL</sub>		5	3.0	8	_	
Max clock frequency		_	10	6.0	17	_	MHz
			15	8.5	20	_	
			<b>5</b> 10	_	35	180	
Min clock pulse width	t₩	— <u>36</u>	10	0	25	80	ns
		~ 为书	15	_	20	50	
Min pulse width		132	5		50	200	
(RESET)	twH	- 60	10		25	80	ns
(===:/			15	_	20	60	
Min set-up time			5	_	8	70	
(DATA-CLOCK)	tsu	_	10	_	4	40	ns
			15	_	0	30	
Min hold time			5	_	6	60	
(DATA-CLOCK)	t <sub>H</sub>	_	10	_	5	30	ns
,			15		4	20	
Min removal time			5	_	0	80	
(RESET-CLOCK)	t <sub>rem</sub>	_	10	_	0	30	ns
,			15	_	0	20	
Max clock input rise time	t <sub>rCL</sub>		5				
Max clock input fall time	t <sub>fCL</sub>	_	10		No limit		μS
			15		i		
Input capacitance	C <sub>IN</sub>	_		_	5	7.5	pF

4

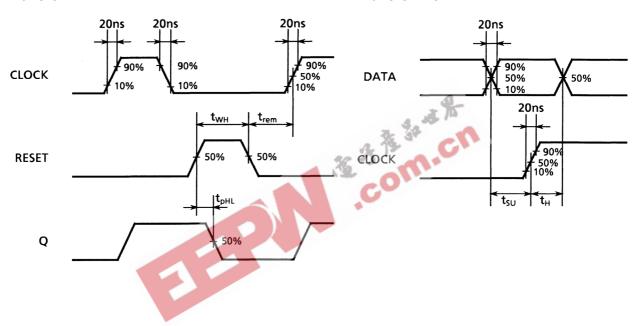
## **Waveforms for Measurement of Dynamic Characteristics**

## Waveform 1



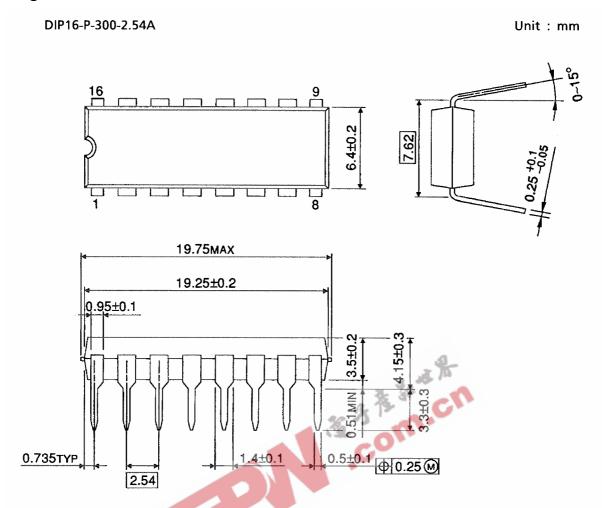
### Waveform 2

### Waveform 3



5

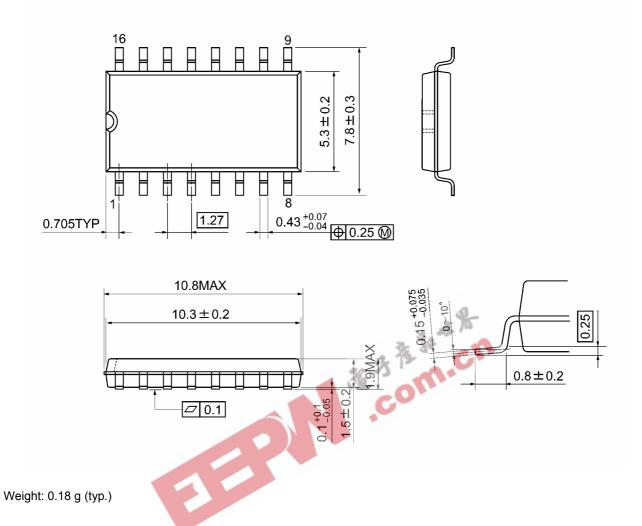
## **Package Dimensions**



Weight: 1.00 g (typ.)

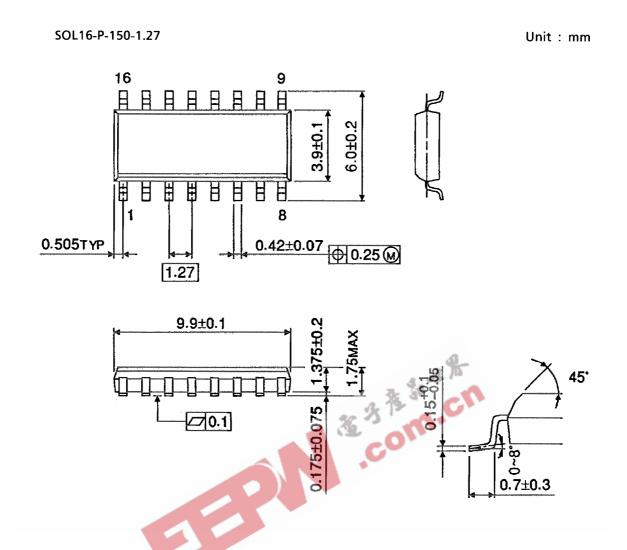
## **Package Dimensions**

SOP16-P-300-1.27A Unit: mm





## **Package Dimensions (Note)**



8

Note: This package is not available in Japan.

Weight: 0.13 g (typ.)

### **RESTRICTIONS ON PRODUCT USE**

20070701-EN GENERAL

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9

2007-10-01